Search strategies for Case _No. 09941761_.
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21/02**
Ex. Andre' Stevenson

USPT,PGPB,JPAB
(((5592007))and (die$2 or dice$2) and
signal$2 and line$2) and isolation$2 and
device$2

USPT,PGPB,JPAB
ll5 and isolation$2 and device$2

USPT,PGPB,JPAB
ll5 and isolation$2 and device$23.

USPT,PGPB,JPAB
((5592007)) and fuse$2

USPT,PGPB,JPAB
((5592007)) and (die$2 or dice$2) and.signal$2
and line$2 and power$2

USPT,PGPB,JPAB
((5592007)) and (die$2 or dice$2) and
signal$2 and line$2

USPT,PGPB,JPAB
((5592007)) and power$2

USPT,PGPB,JPAB
((5592007)) and power$@

USPT,PGPB,JPAB
((5592007)and signal$2 and transistor$2 and
diode$2) and test$3

USPT,PGPB,JPAB
(5592007) and signal$2 and transistor$2 and
diode$2

USPT,PGPB,JPAB
(5592007) and signal$2 and transistor$2 and
diode$2

USPT,PGPB,JPAB
(5592007) and locos

USPT,PGPB,JPAB
(5592007) and test$3 and (connect$2 or
connecting or disconnected$2 or disconnecting)

USPT,PGPB,JPAB
(5592007) and test$3 and (connect$2 or
connecting or disconnected)

USPT,PGPB,JPAB
((5592007)and signal$2 and isolation$2 near
device$2) and test$2

USPT,PGPB,JPAB
(5592007) and signal$2 and isolation$2 near
device$2

USPT,PGPB,JPAB
(((5592007)and dice$2 and wafer and
isolation$2 near device$2)and (die$2 or dice$2)
near test$2) and signal$2 and transistor$2 and
diode$2

USPT,PGPB,JPAB
((5592007)and dice$2 and wafer and
isolation$2 near device$2) and (die$2 or dice$2)
near test$2

USPT,PGPB,JPAB
(dice$2 and wafer and isolation$2 near
device$2) and (die$2 or dice$2) near test$2

USPT,PGPB,JPAB
(5592007) and dice$2 and wafer and
isolation$2 near device$2

USPT,PGPB,JPAB
5592007

USPT,PGPB,JPAB
(((dice$2 and wafer and isolation$2 near
device$2)and (die$2 or dice$2) near test$2)and
transistor$2 and diode$2) and signal$2

USPT,PGPB,JPAB
((dice$2 and wafer and isolation$2 near
device$2)and (die$2 or dice$2) near test$2) and
transistor$2 and diode$2

USPT,PGPB,JPAB
(dice$2 and wafer and isolation$2 near
device$2) and (die$2 or dice$2) near test$2

USPT,PGPB,JPAB
dice$2 and wafer and isolation$2 near device$2

USPT

(dice$2 and wafer and isolation$2 near
device$2) and (die$2 or dice$2) near test$2

USPT
(dice$2 and wafer and isolation$2 near
device$2) and signal$2 near line$2

USPT
dice$2 and wafer and isolation$2 near device$2

USPT
dice$2 and wafer and isolation$2 near device$2
and